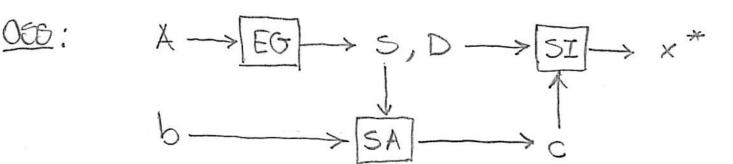
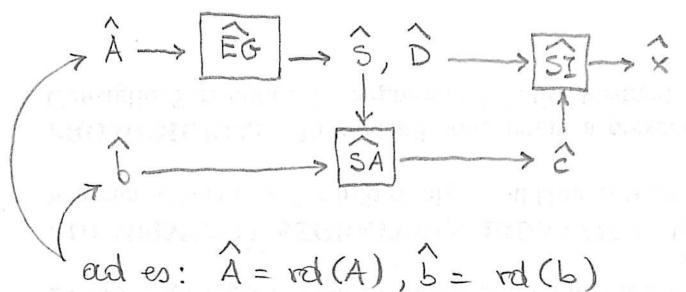


• STUDIO IN F(2,53)



$\xrightarrow{in \mathbb{R}}$   
 $\xrightarrow{in F(2,53)}$



$$\Rightarrow \varepsilon_t \leq \varepsilon_a + \varepsilon_d + \varepsilon_a \varepsilon_d$$

Supponendo  $\varepsilon_a$  piccolo...

Teo (condiz, I) + Teo (condiz, II)  $\Rightarrow$

- $\varepsilon_d \leq c(D) \varepsilon_c \quad (\varepsilon_D = 0)$
- $\hat{\varepsilon}_d \leq c(D) \varepsilon_D \quad (\varepsilon_C = 0)$

$\Rightarrow$  occorre studiare  $c(D)$  !

Ese:  $\gamma \in (0,1)$ ,  $A(\gamma) = \begin{bmatrix} \gamma & 1 \\ 1 & 0 \end{bmatrix}$ ,  $A^{-1}(\gamma) = \begin{bmatrix} 0 & 1 \\ 1 & -\gamma \end{bmatrix}$

$\bullet c_\infty(A(\gamma)) = (1+\gamma)^2 < 4$  (numero d'condiz basso)

$\bullet EG: (S(\gamma), D(\gamma)) = \left( \begin{bmatrix} 1 & 0 \\ 1/\gamma & 1 \end{bmatrix}, \begin{bmatrix} \gamma & 1 \\ 0 & -1/\gamma \end{bmatrix} \right)$

$\bullet c_\infty(D(\gamma)) \geq \frac{1}{\gamma^2}$  NON LIMITATO per  $\gamma \in (0,1)$

$$\varepsilon_D = \frac{\|\hat{D} - D\|}{\|D\|}, \quad \varepsilon_C = \frac{\|\hat{C} - C\|}{\|C\|}$$

$$D, \varepsilon_D \xrightarrow{c, \varepsilon_C} [SI] \rightarrow x^*, \varepsilon_d$$

$$\hat{x} = \hat{SI}(\hat{D}, \hat{c}), \quad x^* = SI(D, c)$$

$$\tilde{x} = SI(\hat{D}, \hat{c})$$

$$\Rightarrow \varepsilon_t = \frac{\|\hat{x} - x^*\|}{\|x^*\|} \leq \frac{\|\hat{x} - \tilde{x}\|}{\|\tilde{x}\|} \frac{\|\tilde{x}\|}{\|x^*\|} + \varepsilon_a + \varepsilon_d$$

$$\leq \frac{\|\tilde{x} - x^*\|}{\|x^*\|} + 1$$

Oss: EGPP (EG con Pivoting Parziale)

"al passo k, si utilizza come pivot:  $\max_{i \geq k} |a_{ik}^{(k)}|$ "

Ese (continua):

• EGPP:  $(P, S(\gamma), D(\gamma)) = \left( \begin{bmatrix} 0 & 1 \\ 1 & 0 \end{bmatrix}, \begin{bmatrix} 1 & 0 \\ \gamma & 1 \end{bmatrix}, \begin{bmatrix} 1 & 0 \\ 0 & 1 \end{bmatrix} \right)$

con  $c_\infty(D) = 1$

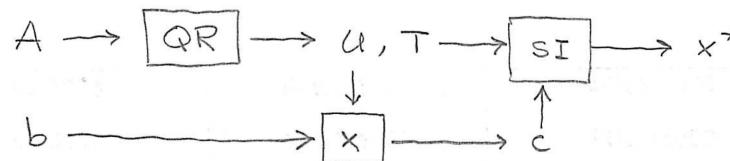
In generale, con EGPP si ottiene  $c(D) \leq m 2^n c(A)$

Ese (terza casella):  $T \in \mathbb{R}^{n \times n}$  tr sup; verif che  $\|T\|_\infty \geq \max_k |t_{kk}|$

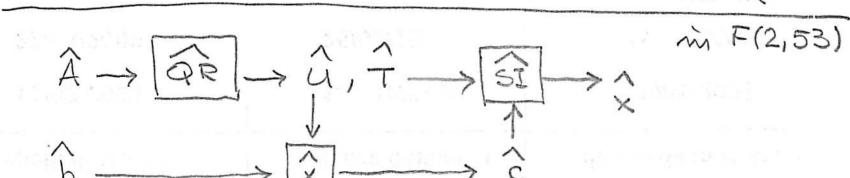
e q.dich, se  $T$  invert, che  $\|T^{-1}\|_\infty \geq \max_k |t_{kk}^{-1}|$ .

$$\Rightarrow c_\infty(T) \geq \frac{\max_k |t_{kk}|}{\min_k |t_{kk}|}$$

Oss:



$\varepsilon_T, \varepsilon_C \dots$



$$T, \varepsilon_T \xrightarrow{c, \varepsilon_C} [SI] \rightarrow x^*, \varepsilon_d$$

- Teo condiz  $\Rightarrow$
- $\varepsilon_d \leq c(T) \varepsilon_T \quad (\varepsilon_C = 0)$
  - $\hat{\varepsilon}_d \leq c(T) \varepsilon_C \quad (\varepsilon_T = 0)$

$\Rightarrow$  occorre studiare  $c(T)$  !

Oss:  $(\mathbb{R}^m, \|\cdot\|_2)$  •  $T = U^T A \Rightarrow \|T\|_2 \leq \|A\|_2$

•  $T^{-1} = A^{-1}U \Rightarrow \|T^{-1}\|_2 \leq \|A^{-1}\|_2$

$$\Rightarrow \text{c}_2(T) \leq \text{c}_2(A)$$

Ese (per caso):  $U$  ortogonale  
 $\Rightarrow \|U\|_2 = 1$

Oss: esiste il seg

TEO:  $\hat{x} \in \mathbb{R}^m$  ottenuto dalla procedura

(I)  $(\hat{S}, \hat{D}) = \widehat{\text{EG}}(A)$

(II)  $\hat{c} = \widehat{\text{SA}}(\hat{S}, b)$

(III)  $\hat{x} = \widehat{\text{SI}}(\hat{D}, \hat{c})$

Allora:  $\exists \delta A \in \mathbb{R}^{m \times m}$  t.c.

•  $\|\delta A\| \leq \mu \|\hat{S}\| \|\hat{D}\|$  [a pres. di macchina]

•  $(A + \delta A) \hat{x} = b$

OVVERO:  $\hat{x}$  è la soluz CALCOLATA op in IR di un sist  
di eq ottenuto perturbando "foco" le  
matrice del sist originari.

Oss (int fisica): se il sist  $Ax = b$  ha origin finice,

i dati  $A$  e  $b$  sono affetti da errore;

se  $\delta A \approx$  errore di origin finice, allora

$\hat{x}$  è "finicam significative"